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Alessandro Andreani^{1,2}, Marco Bassani^{1,3}, Paolo Cova^{1,3}, Nicola Delmonte^{1,3}, Niccolò Gallice^{1,2}, Massimo Lazzaroni^{1,2}, <u>Danilo Santoro^{1,3}</u>, Andrea Zani¹

¹INFN Sezione di Milano ²Università degli Studi di Milano ³Università degli Studi di Parma

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System overview

- DC-DC boost converter: HV for SiPM bias at cold
- Evolution in relation to DUNE collaboration needs
- Power supply provided by PoC (Power optical Converter): 5 V to 7 V range
- Typical boost topology with MOS transistor: output voltage up to 50 V
- **PWM generation** with two possible controls:
 - Inner feedback setting output voltage at nominal point (e.g. 48 V)
 - Optical input to change the setting voltage within few volts



Content

- GaAs Power optical Converter (PoC)
- DC-DC boost design
 - Component characterization
 - Performance
- Control design
- OpAmp characterization
- Conclusions





GaAs PoC

5 V to 7 V range power supply from PoC:

- Tests with Broadcom AFBR-406L based on GaAs technology
- Powered by 808 nm Lumics laser (8 W max)
- Multimode 200 µm core fiber
- B1505A Semiconductor Analyzer to fix the output voltage and measure the current
- RTD sensor used for PoC temperature check





GaAs PoC

5 V to 7 V range power supply from PoC:

- Curves labeled according to laser input current ($P_{opt} \propto I$)
- Reference: 3 A \rightarrow 1.5 W_{opt}
- Measurements both at RoomT and at LN₂ temperature
- Voltage increases from 7 V to 8 V (at 3000 mA) between Room and LN₂ temperature



DC characterization of MOSFET and diode

MOSFETscharacterized at Room and at LN2 temperature with a B1505A Semiconductor Analyzer:

- $I_D vs V_{GS}$ (at various V_{DS}) to measure the **threshold**
- V_{DS} vs I_D (at various V_{GS}) to measure the **on resistance** $R_{DS(on)}$

Diode forward I-V curve to measure the junction voltage V_D





MOSFET results



- Drain current vs Gate-to-Source voltage: threshold increases of about 0.6 V (77 K)
- On resistance reduces considerably at 77 K, for NTF resulting in 30 m Ω .



Diode results

- Diode current vs applied voltage (forward bias mode): junction
 voltage increase of about 0.4 V
- Same behavior between
 BAV16W and BAS16LD diodes





AC characterization of inductor

- Tests on B8244T1106K05010 mH inductor
- HP 4395A Impedance Analyzerused in Reflection mode to analyze the impedance as a function of frequency

Model:



• Results fitted and parameters extracted



10 17/05/22 D. Santoro | Bias over fiber developments in Milan

• Fitted parameters are:

T [K]	R [Ω]	L [mH]	C [pF]
300 K	106	10	5
$77\mathrm{K}$	20	8	5

- Resonance frequency is 700 kHz (800 kHz) at 300 K (77 K): good at f_{SW} = 100 kHz
- Series resistance drops drastically at 77 K: DC-DC converter better performances





DC-DC boost converter

Components selection:

- MOSFET: NTF3055L108T1G, ZXMN10A07FTA, VN2460N8, 2N7002H6327XTSA2, 2N7002CK
 - Lowest on-resistance
- Switching Diode: BAV16W, BAS16LD
 - Very similar device, slightly better max current
- Inductor: B82442T1125K000 (680 uH, 1 MHz), B8244T1106K050 (10mH, 100 kHz)
 - Good to mitigate input current ripple
- Capacitor: C1812C104J1GACTU (COG 100 nF)
 - COG for cryogenic use

N. Gallice et al., "Development of a cryogenic DC-DC Boost Converter: devices characterization and first prototype measurements," 2022 IEEE International Instrumentation and Measurement Technology Conference (I2MTC), Ottawa, ON, Canada, 2022, pp. 1-6, doi: 10.1109/I2MTC48687.2022.9806646.



DC-DC boost first prototype

- DC input provided by linear supply
- Control signal produced by Pattern
 Generator
- System tested at room and LN2 temperature with different inputs (4 V, 5 V) and different duty cycles [0.1, 0.93]







- Output voltage at RoomT limited by the inductor series resistor. At LN2 T, it is
 possible to reach 50 V at 93% of Duty Cycle
- The efficiency at LN2 is always greater than 60%



DC-DC prototype results



Output voltage FFT measurements at 77K (blue) and 300K (red)



Content

- System overview \checkmark
- GaAs Power optical Converter (PoC) ✓
- DC-DC boost design \checkmark
 - Component characterization \checkmark
 - Performance \checkmark
- Control design
- OpAmp characterization
- Conclusions



Control design

Internal feedback: output voltage control at desired set point

The set point can be:

- Nominal: set at design stage and fixed throughout the entire run (standalone mode)
- External: set point adjusted through external communication (in case of failure, nominal set-point)





PWM generation

- PWM (Pulse Width Modulator)
 generation based on two comparators
- Comparators tested to work in LN 2
- First comparator set in a positive feedback circuit: oscillator
- Second comparator produces the PWM through triangle waveform (carrier) and voltage set level (modulation) inputs
- Tests at f_{SW} from ~100 kHz to ~1 MHz





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Control feedback

- Output of DC-DC boost converter compared with nominal working point (error amplifier)
- Operational amplifier tested to work in LN₂
- 48.2 V generated and kept constant by the internal feedback at LN₂ temperature (5.5 V input)
- 100 k\Omega load \rightarrow 485 μ A
- Overall current consumption: 10.3 mA ~ 50% efficiency







External set point

- External PWM signal drove through optical fiber: **external set point**
- Reference level changes
- AC-coupling in case of external PWM, otherwise reference set by R2-R3 divider
- E.g. with f_{SW} ~100 kHz, 5.5 V input, 20 % external duty-cycle: boost voltage output ~ 36 V (max = 51 V)





Future developments

- Adding card for external DC-DC boost converter control
- Connection pins available on the DC-DC boost converter PCB
- Shield integration for EMI reduction

Connection pads for shield integration



External card slot



Component characterization: OpAmps

First characterization circuit for OpAmps

- DUT: OpAmp LMV321
- Input offset voltage test
- DUT in climate chamber with LN2 injection
- Offset recovery at each temperature step
- Automatic test bench control





Characterization testbed

• DUT in climate chamber with LN2 injection





Early experimental results

- DUT: LMV321
- Temperature and input offset voltage data recovery
- Low measurement system sensibility





Revised characterization circuit

- OpAmp characterization for cyogenics:
 - Input offest voltage;
 - Bias current
 - PSRR
 - Quiescent current
- General circuit editable for all Op Amp parameters extraction
- OpAmps as DUT:
 - MCP6291
 - MCP6N11
 - LMV321
 - TLC271
 - AD8293





Future developments

- Warm test card with Auxiliary OpAmp at 300 K
- Cold test card in climate chamber with LMV321

Issues:

- Revised PCB in arrival
- Dewar with more capacity necessary
- High-rate multiplexer for data acquisition unit necessary



